L Number	Hits	Search Text	DB	Time stamp
-	71	3567$.ccls. and (gate adj oxide)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/02 14:04
-	59	3567$.ccls. and (gate adj oxide)	USPAT	2003/07/02 14:05
-	5	(gate adj oxide) and thickness and (high$1k) and scatter$	USPAT	2003/07/02 15:19
-	55	3567$.ccls. and (gate adj oxide) and thickness	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/02 15:25
-	231	halliyal-arvind singh-bhanwar subramanian-ramkumar).in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/02 15:26
-	18	halliyal-arvind singh-bhanwar subramanian-ramkumar).in. and (gate adj oxide) and thickness	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/02 15:26
-	22	3567$.ccls. and (gate adj oxide) and (thickness or uniform$) and scatter$	USPAT	2003/07/08 14:44
-	28	3567$.ccls. and (gate adj oxide) and (thickness or uniform$) and scatter$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/08 16:56
-	9	("4710030" | "4750822" | "5298970" | "5608526" | "5798837" | "5978074" | "6060374" | "6081330" | "6391099").PN.	USPAT	2003/07/08 16:18
-	5	("4710030" | "4750822" | "5298970" | "5608526" | "5798837" | "5978074" | "6060374" | "6081330" | "6391099").PN. and scatter$	USPAT	2003/07/08 16:19
-	0	("4710030" | "4750822" | "5298970" | "5608526" | "5798837" | "5978074" | "6060374" | "6081330" | "6391099").PN. and scatter$ and (gate adj oxide)	USPAT	2003/07/08 16:29
-	32	356$.ccls. and (gate adj oxide) and (thickness or uniform$) and scatter$	USPAT	2003/07/08 16:30
-	30	356$.ccls. and (gate adj oxide) and (thickness or uniform$) and scatter$ not 3567$.ccls.	USPAT	2003/07/08 16:30
-	33	256$.ccls. and (gate adj oxide) and (thickness or uniform$) and scatter$ not 356$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/08 16:45
-	622	((gate adj oxide) with (thickness or uniform$)) and scatter$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 12:10
-	19	((gate adj oxide) with (thickness or uniform$)) and scatter$.clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:46
-	2	356/630-632.ccls. and (gate adj oxide) and scatter$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:26
-	14	((gate adj oxide) with (thickness or uniform$)).ab. and scatter$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 12:38

-	0	("5860054" "6060374" "5880040").pn. and scatter$	USPAT	2003/07/09 13:37
-	3	("5860054" "6060374" "5880040").pn.	USPAT	2003/07/09 15:11
-	9452	(438/163,786,514,14-18,769 257/e21.193,e29.162 700/101,108,109 702/191).ccls. ((gate adj oxide) with thickness or uniform$) and scatter$ and nitrid$ or nitrogen$)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 12:41
-	9035	438/163,786,514,14-18,769 257/e21.193,e29.162 700/101,108,109 702/191).ccls. ((gate adj oxide) with thickness or uniform$) and scatter$.ab. and nitrid$ or nitrogen$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 12:41
-	4	(438/163,786,514,14-18,769 257/e21.193,e29.162 700/101,108,109 702/191).ccls. and ((gate adj oxide) with thickness or uniform$) and scatter$.ab. and nitrid$ or nitrogen$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 12:44
-	1	(438/163,786,514,14-18,769 257/e21.193,e29.162 700/101,108,109 702/191).ccls. and ((gate adj oxide) with thickness or uniform$).ab. and scatter$ and nitrid$ or nitrogen$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 12:45
-	31	438/163,786,514,14-18,769 257/e21.193,e29.162 700/101,108,109 702/191).ccls. and ((gate adj oxide) with thickness or uniform$) and scatter$ and nitrid$ or nitrogen$)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 15:43
-	3	."6528433" "5904523" "6060374").pn.	USPAT	2003/07/09 15:12
-	2	."20010023900" "20030042432").pn.	US-PGPUB	2003/07/09 15:13
-	116	356/630-631.ccls. and (semiconductor or wafer) and scatter$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:26
-	10	356/630-631.ccls. and (semiconductor or wafer) and scatter$.ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 11:43
-	1	356/630-631.ccls. and (semiconductor or wafer) and (scatterometry with thickness)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:36
-	0	(scatterometry with nitrogen) and (semiconductor or wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:36
-	0	.scatterometry with nitrogen)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:36
-	679	scatter$ with nitrogen)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:36
-	195	scatter$ with nitrogen) and semiconductor or wafer or (gate adj oxide))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:37
-	55	scatter$ with nitrogen) and semiconductor or wafer or (gate adj oxide)) and scatter$.ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:39

-	47	(scatter$ with nitrogen) and (semiconductor or wafer or (gate adj oxide) and scatter$.ab. not (electron near4 beam)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:40
-	26	scatter$ with nitrogen) and semiconductor or wafer or (gate adj oxide) and (scatter$ and (nitrogen or nitride$)).ab. not (electron near4 beam)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/09 16:40
-	9	("5867276" | "5877860" | "5890838" | "6051348" | "6081334" | "6141107" | "6245664" | "6393886" | "6423977").PN.	USPAT	2003/07/10 11:16
-	1	("5867276" | "5877860" | "5890838" | "6051348" | "6081334" | "6141107" | "6245664" | "6393886" | "6423977").PN. and scatter$.ab.	USPAT	2003/07/10 11:18
-	4	("4713642" | "5164790" | "5241369" | "5703692").PN.	USPAT	2003/07/10 11:17
-	4	("5867276" | "5877860" | "5890838" | "6051348" | "6081334" | "6141107" | "6245664" | "6393886" | "6423977").PN. and scatteromet$	USPAT	2003/07/10 11:18
-	17	356/630-632.ccls. and (semiconductor or wafer) and scatterom$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 12:01
-	16	356/630-632.ccls. and (semiconductor or wafer) and scatterom$ not scatter$.ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 11:43
-	6	356/237.4,137.5.ccls. and (semiconductor or wafer) and scatterom$ and thickness	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/11 14:17
-	7	250/559.27.ccls. and (semiconductor or wafer) and scatterom$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 11:55
-	1	250/559.27.ccls. and (semiconductor or wafer) and scatterom$	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 11:55
-	21	356/630-632.ccls. and scatterom$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 12:01
-	10	356/630-632.ccls. and scatterom$	USPAT	2003/07/10 12:01
-	154	356/630-632.ccls. and scatter$	USPAT	2003/07/10 12:01
-	20	356/630-632.ccls. and scatter$.ab.	USPAT	2003/07/10 12:02
-	20	356/630-632.ccls. and scatter$.ab. and scatter$	USPAT	2003/07/10 12:02
-	35	356$.ccls. and (semiconductor or wafer) and scatterom$.ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 14:17
-	8	("3393624" | "5867276" | "5923423" | "6100985" | "6259521" | "6266125" | "6298253" | "6424417").PN.	USPAT	2003/07/10 15:27
-	2	("3393624" | "5867276" | "5923423" | "6100985" | "6259521" | "6266125" | "6298253" | "6424417").PN. and (nitrogen$ or nitride$)	USPAT	2003/07/10 15:27

-		61	(438/263,736,514,14-18,769 257,'e21.193,e29.162 700/121,108,109 702/181).ccls. and ((gate adj oxide) with cvd)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 15:54
-		19	(438/263,736,514,14-18,769 257,'e21.193,e29.162 700/121,108,109 702/181).ccls. and (gate adj oxide).ab. and ((gate adj oxide) with cvd)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 15:57